•	Sear	ch	Note	es :	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/702,090	KUDO ET AL.
Examiner	Art Unit
Dru M. Parries	2836

	SEAR	CHED	
Class	Subclass	Date	Examiner
307	82	4/23/2007	DMP
•			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		8		
	ce search ucted	4/23/2007	DMP	

23/2007	DMP